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218478US-227607-8011-2-PCT

IN THE UNITED STATES PATENT & TRADEMARK OFFICE
IN RE APPLICATION OF :

YASUJI HIRAMATSU ET AL. : ATTN: APPLICATION DIVISION

SERIAL NO: 10/030,123 :

FILED: JANUARY 24, 2002 :

FOR: SEMICONDUCTOR-PRODUCING/:
EXAMINING DEVICE

361a
3-20-03

PRELIMINARY AMENDMENT

ASSISTANT COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

SIR:

Prior to a first examination on the merits, please amend the above-identified application as follows:

IN THE CLAIMS

Please amend Claims 3 and 4 to read as follows:¹

3. (Amended) The semiconductor-producing/examining device according to claim 1,

wherein

the connection between said conductor layer and said external terminal, or

the connection between said another conductor layer and said external terminal

is performed through a non-oxidizable metal layer.

¹A marked-up copy of the amendments is attached hereto.